

MD7003, F (SILICON)

MD7003A, AF

MD7003B

MQ7003

MULTIPLE SILICON ANNULAR TRANSISTORS

... designed for use as high-gain, low-noise differential amplifiers, front end detectors, and temperature compensation applications.

- Low Collector-Emitter Saturation Voltage - $V_{CE(sat)} = 0.25 V_{dc}$ (Typ) @ $I_C = 10 \text{ mA}_{dc}$
- DC Current Gain Specified @ $100 \mu\text{A}_{dc}$ and 10 mA_{dc}
- High Current-Gain-Bandwidth Product - $f_T = 300 \text{ MHz}$ (Typ) @ $I_C = 5.0 \text{ mA}_{dc}$

MAXIMUM RATINGS

Rating	Symbol	Value	Unit	
Collector-Emitter Voltage	V_{CE0}	40	Vdc	
Collector-Base Voltage	V_{CB}	50	Vdc	
Emitter-Base Voltage	V_{EB}	5.0	Vdc	
Collector Current - Continuous	I_C	50	mA _{dc}	
		One Die	All Die Equal Power	
Total Power Dissipation @ $T_A = 25^\circ\text{C}$	P_D	550	600	mW
MD7003, A, B		350	400	
MD7003F, AF		400	600	
MQ7003				
Derate above 25°C		3.14	3.42	mW/°C
MD7003, A, B		2.0	2.28	
MD7003F, AF		2.28	3.42	
MQ7003				
Total Power Dissipation @ $T_C = 25^\circ\text{C}$	P_D	1.4	2.0	Watts
MD7003, A, B		0.7	1.4	
MD7003F, AF		0.7	2.8	
MQ7003				
Derate above 25°C		8.0	11.4	mW/°C
MD7003, A, B		4.0	8.0	
MD7003F, AF		4.0	16	
MQ7003				
Operating and Storage Junction Temperature Range	T_J, T_{stg}	-65 to +200	°C	

THERMAL CHARACTERISTICS

Characteristic	Symbol	One Die	All Die Equal Power	Unit
Thermal Resistance, Junction to Ambient	$R_{\theta JA(1)}$	319	292	°C/W
MD7003, A, B		500	438	
MD7003F, AF		438	292	
MQ7003				
Thermal Resistance, Junction to Case	$R_{\theta JC}$	125	87.5	°C/W
MD7003, A, B		250	125	
MD7003F, AF		250	62.6	
MQ7003				
Coupling Factor		Junction to Ambient	Junction to Case	%
MD7003, A, B		83	40	
MD7003F, AF		75	0	
MQ7003 (Q1-Q2)		57	0	
MQ7003 (Q1-Q3 or Q1-Q4)		55	0	

(1) $R_{\theta JA}$ is measured with the device soldered into a typical printed circuit board.

PNP SILICON DUAL TRANSISTORS

MD7003A,B

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	0.51	0.40	0.335	0.370
B	7.75	8.51	0.305	0.335
C	3.81	4.70	0.150	0.185
D	0.81	0.52	0.031	0.021
E	5.08 BSC		0.200 BSC	
F	0.71	0.86	0.028	0.034
G	0.74	1.14	0.029	0.045
H	12.70		0.500	
J	45° BSC		45° BSC	
K	2.54 BSC		0.100 BSC	
L				
M				
N				

STYLE 1: 1. COLLECTOR, 2. BASE, 3. EMITTER, 4. OMITTED, 5. BASE, 6. EMITTER, 7. COLLECTOR, 8. OMITTED

CASE 604-07

MD7003F, AF

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	6.10	7.36	0.240	0.290
B	2.92	4.06	0.115	0.160
C	0.76	2.03	0.030	0.080
D	0.36	0.48	0.014	0.019
E	0.76	0.15	0.030	0.006
F	1.27 BSC		0.050 BSC	
G		0.80		0.031
H	3.81		0.150	
J				
K				
L	2.54 BSC		0.100 BSC	
M				
N				
O				
P				
Q				
R				

STYLE 1: 1. BASE, 2. EMITTER, 3. BASE, 4. EMITTER, 5. BASE, 6. COLLECTOR, 7. COLLECTOR

CASE 610A-03

MQ7003

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	6.10	6.39	0.240	0.252
B	0.76	2.03	0.030	0.080
C	0.25	0.48	0.010	0.019
D	0.88	0.15	0.035	0.006
E	1.27 BSC		0.050 BSC	
F	0.13	0.80	0.005	0.031
G		0.38		0.015
H	6.35		0.250	
I	18.80		0.740	
J	8.20		0.010	
K				
L				
M				
N				
O				
P				
Q				
R				
S				

STYLE 1: 1. COLLECTOR, 2. BASE, 3. EMITTER, 4. NOT CONNECTED, 5. EMITTER, 6. BASE, 7. COLLECTOR, 8. COLLECTOR, 9. BASE, 10. EMITTER, 11. NOT CONNECTED, 12. EMITTER, 13. BASE, 14. COLLECTOR

CASE 607-04



NJ Semi-Conductors reserves the right to change test conditions, parameter limits and package dimensions without notice. Information furnished by NJ Semi-Conductors is believed to be both accurate and reliable at the time of going to press. However, NJ Semi-Conductors assumes no responsibility for any errors or omissions discovered in its use. NJ Semi-Conductors encourages customers to verify that datasheets are current before placing orders.

MD7003,A,AF,B,F, MQ7003 (continued)

THERMAL COUPLING AND EFFECTIVE THERMAL RESISTANCE	
<p>In multiple chip devices, coupling of heat between die occurs. The junction temperature can be calculated as follows:</p> $(1) \Delta T_{J1} = R_{\theta 1} P_{D1} + R_{\theta 2} K_{\theta 2} P_{D2} + R_{\theta 3} K_{\theta 3} P_{D3} + R_{\theta 4} K_{\theta 4} P_{D4}$ <p>Where ΔT_{J1} is the change in junction temperature of die 1 $R_{\theta 1}$ thru 4 is the thermal resistance of die 1 through 4 P_{D1} thru 4 is the power dissipation in die 1 through 4 $K_{\theta 2}$ thru 4 is the thermal coupling between die 1 and die 2 through 4.</p> <p>An effective package thermal resistance can be defined as follows:</p> $(2) R_{\theta (EFF)} = \Delta T_{J1} / P_{DT}$ <p>Where: P_{DT} is the total package power dissipation.</p>	<p>Assuming equal thermal resistance for each die, equation (1) simplifies to</p> $(3) \Delta T_{J1} = R_{\theta 1} (P_{D1} + K_{\theta 2} P_{D2} + K_{\theta 3} P_{D3} + K_{\theta 4} P_{D4})$ <p>For the conditions where $P_{D1} = P_{D2} = P_{D3} = P_{D4}$, $P_{DT} = 4P_D$ equation (3) can be further simplified and by substituting into equation (2) results in</p> $(4) R_{\theta (EFF)} = R_{\theta 1} (1 + K_{\theta 2} + K_{\theta 3} + K_{\theta 4}) / 4$ <p>Values for the coupling factors when either the case or the ambient is used as a reference are given in the table on page 1. If significant power is to be dissipated in two die, die at the opposite ends of the package should be used so that lowest possible junction temperatures will result.</p>

ELECTRICAL CHARACTERISTICS ($T_A = 25^{\circ}\text{C}$ unless otherwise noted.)

Characteristic	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS					
Collector-Emitter Breakdown Voltage (1) ($I_C = 10 \mu\text{A dc}$, $I_B = 0$)	BV_{CEO}	40	—	—	Vdc
Collector-Base Breakdown Voltage ($I_C = 10 \mu\text{A dc}$, $I_E = 0$)	BV_{CBO}	50	—	—	Vdc
Emitter-Base Breakdown Voltage ($I_E = 10 \mu\text{A dc}$, $I_C = 0$)	BV_{EBO}	5.0	—	—	Vdc
Collector Cutoff Current ($V_{CB} = 30 \text{ Vdc}$, $I_E = 0$)	I_{CBO}	—	—	100	nA dc
ON CHARACTERISTICS					
DC Current Gain (1) ($I_C = 100 \mu\text{A dc}$, $V_{CE} = 10 \text{ Vdc}$) ($I_C = 10 \text{ mA dc}$, $V_{CE} = 10 \text{ Vdc}$)	h_{FE}	40 50	350 350	— —	—
Collector-Emitter Saturation Voltage ($I_C = 10 \text{ mA dc}$, $I_B = 1.0 \text{ mA dc}$)	$V_{CE(sat)}$	—	0.25	0.35	Vdc
Base-Emitter Saturation Voltage ($I_C = 10 \text{ mA dc}$, $I_B = 1.0 \text{ mA dc}$)	$V_{BE(sat)}$	—	0.6	1.0	Vdc
DYNAMIC CHARACTERISTICS					
Current-Gain—Bandwidth Product ($I_C = 5.0 \text{ mA dc}$, $V_{CE} = 20 \text{ Vdc}$, $f = 100 \text{ MHz}$)	f_T	200	300	—	MHz
Output Capacitance ($V_{CB} = 10 \text{ Vdc}$, $I_E = 0$, $f = 100 \text{ kHz}$)	C_{ob}	—	3.0	6.0	pF
Input Capacitance ($V_{BE} = 2.0 \text{ Vdc}$, $I_C = 0$, $f = 100 \text{ kHz}$)	C_{ib}	—	2.0	8.0	pF
Noise Figure ($I_C = 100 \mu\text{A dc}$, $V_{CE} = 10 \text{ Vdc}$, $R_S = 3.0 \text{ k Ohms}$, $f = 10 \text{ Hz to } 15.7 \text{ kHz}$)	NF	—	2.0	—	dB
MATCHING CHARACTERISTICS					
DC Current Gain Ratio (2) ($I_C = 100 \mu\text{A dc}$, $V_{CE} = 10 \text{ Vdc}$)	MD7003A,AF MD7003B	h_{FE1}/h_{FE2}	0.76 0.85	— —	1.0 1.0
Base-Emitter Voltage Differential ($I_C = 100 \mu\text{A dc}$, $V_{CE} = 10 \text{ Vdc}$)	MD7003A,AF MD7003B	$ V_{BE1} - V_{BE2} $	— —	— —	25 15

(1) Pulse Test: Pulse Width $\leq 300 \mu\text{s}$, Duty Cycle $\leq 2.0\%$.
 (2) The lowest h_{FE} reading is taken as h_{FE1} for this ratio.